

<b>Notice of References Cited</b>	Application/Control No. 10/763,394	Applicant(s)/Patent Under Reexamination PARK ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0027121 A1	02-2004	Choi et al.	324/253
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 2001099654 A	04-2001	Japan	YAMAZAWA et al.	G01C 17/30
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	English translation of the Detailed Description of JP 2001099654 A
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	X	

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